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INFORMATION DISCLOSURE STATEMENT BY APPLICANT		SNDK.256US0	10/052,924
(Use several sheets if necessary)		Applicant(s)	
JUL 09 2003 JC42		Mokhlesi et al.	
		Filing Date	Group
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*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
WWT	4,630,086	12/16/86	Sato et al.			
	5,172,338	12/15/92	Mehrotra et al.			
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	5,418,752	5/23/95	Harari et al.			
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U.S. Published Patent Application Documents

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate

Foreign Patent Documents

							Translation
		Document	Date	Country	Class	Subclass	Yes

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

WWT	11	Bauza et al., "In-Depth Exploration of Si-SiO ₂ Interface Traps in MOS Transistors Using the Charge Pumping Technique," <i>IEEE Transactions on Electron Devices</i> , Vol. 44, No. 12, December 1997, pp. 2262-2266.
	12	Bloom, et al., "1/f Noise Reduction of Metal-Oxide-Semiconductor Transistors by Cycling from Inversion to Accumulation," <i>Appl. Phys. Lett.</i> 58 (15), 15 April 1991, pp. 1664-1666.
	13	Dierickx et al., "The Decrease of "Random Telegraph Signal" Noise in Metal-Oxide-Semiconductor Field-Effect Transistors When Cycled from Inversion to Accumulation," <i>J. Appl. Phys.</i> 71 (4), 15 February 1992.
	14	Hung et al., "Random Telegraph Noise of Deep-Submicrometer MOSFET's," <i>IEEE Electron Device Letters</i> , Vol. 11, No. 2, February 1990, pp. 90-92.
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